
Proposed IEEE Std. P1159.1
Task Force on a Guide for Recorder Qualification and Data Acquisition Requirements
for Characterization of PQ Events

Meeting Minutes

IEEE PES Winter Meeting, New York, NY
February 3, 1997, 1:30 - 2:30 PM

The meeting was called to order by Roger Bergeron, chairman and attendees were asked to sign the attendance list for 1159.1.

Comments on the minutes of the July 29, 1996 meeting were requested. There being none, the minutes were approved as submitted.

Old Business:

- The project scope as presented in the PAR was discussed. Roger reminded contributors that it is important to avoid patented techniques unless a release is obtained. In that regard, Item 9.a.3 on the PAR should be checked YES.
- Chapter Chair Reports:
 - Transients - Rich Bingham: A draft of the transients section will be e-mailed to Roger Bergeron and Larry Morgan. An electronic copy will be sent to IEEE.
 - Short Duration RMS Variations - Dan Sabin: This section will need to discuss phase shift, RMS averaging (over what time?), and RMS envelope.
 - Long Duration RMS Variation - Cheri Warren: No Report
 - Voltage Imbalance - Doug Door: No Report
 - Waveform Distortion - Jeff Lamoree: No report
 - Voltage Fluctuations - Tom Key: No Report
 - Frequency - Dennis Hansen: Dennis will be replaced by Greg Rauch
- Sample rates and envelope size need to be specified for each type of event. In addition, it must be determined how to characterize multiple events which occur at the same time. e.g., sag and swell on a three phase system associated with a single phase-to-ground fault.
- Items which may need to be included in the discussion are as follows:
 - Time sequence of f - f event
 - Frequency response - rate/s
 - Envelope - # cycles
 - Phase measured
 - A-D resolution
 - Requirement for current?
 - Application - revenue meter, digital watt meter, long term measurement

Misuse of instrument

- IEC 1000-4-7

This standard will include three classes of instrumentation:

Laboratory

High quality field unit

General purpose

The purpose of measurement is important. e.g., permanent installation, diagnostic testing, standards compliance. Different algorithms may result in different measurement results. It is suggested that the rationale of the IEC Standard be the starting point for development of 1159.1.

New Business:

- Chapter Chairs are requested to have an outline of their chapters for the next meeting.

There being no further business, the meeting was adjourned.

David B. Vannoy, Acting Secretary

attach:

Attendance

Transients subsection - R. Bingham